

# M66257FP

 $5120 \times 8$ -Bit  $\times 2$  Line Memory (FIFO)

REJ03F0251-0200 Rev.2.00 Sep 14, 2007

#### **Description**

The M66257FP is a high-speed line memory with a FIFO (First In First Out) structure of 5120-word × 8-bit double configuration which uses high-performance silicon gate CMOS process technology.

It allows simultaneous output of 1-line delay data and 2-line delay data, and is most suitable for data correction over multiple lines.

It has separate clock, enable and reset signals for write and read, and is most suitable as a buffer memory between devices with different data processing throughput.

#### **Features**

Memory configuration:
 5120 words × 8 bits × 2 (dynamic memory)

High-speed cycle: 25 ns (Min)
High-speed access: 18 ns (Max)
Output hold: 3 ns (Min)

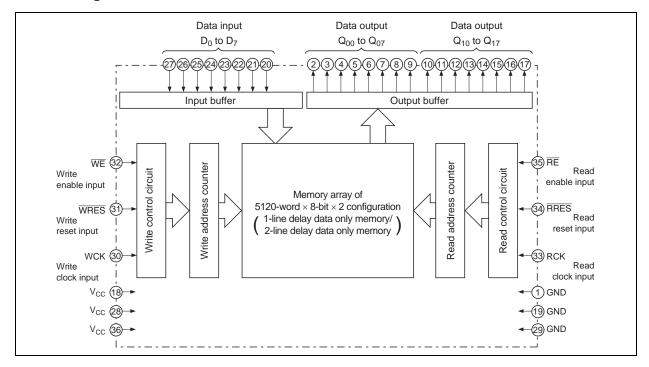
· Fully independent, asynchronous write and read operations

Output: 3 states
 Q<sub>00</sub> to Q<sub>07</sub>: 1-line delay
 Q<sub>10</sub> to Q<sub>17</sub>: 2-line delay

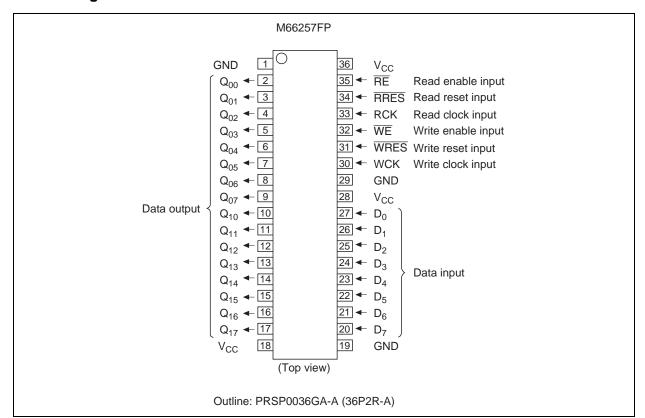
### **Application**

Digital photocopiers, high-speed facsimile, laser beam printers.

#### **Block Diagram**



### **Pin Arrangement**



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## **Absolute Maximum Ratings**

(Ta = 0 to  $70^{\circ}$ C, unless otherwise noted)

Item	Symbol	Ratings	Unit	Conditions
Supply voltage	V <sub>CC</sub>	-0.5 to +7.0	V	A value based on
Input voltage	Vi	−0.5 to V <sub>CC</sub> + 0.5	V	GND pin
Output voltage	Vo	$-0.5$ to $V_{CC}$ + $0.5$	V	
Power dissipation	Pd	660	mW	Ta = 25°C
Storage temperature	Tstg	-65 to 150	°C	

## **Recommended Operating Conditions**

Item	Symbol	Min	Тур	Max	Unit
Supply voltage	Vcc	4.5	5	5.5	V
Supply voltage	GND	_	0	_	V
Operating ambient temperature	Topr	0	_	70	°C

### **Electrical Characteristics**

(Ta = 0 to 70°C,  $V_{CC} = 5 \text{ V} \pm 10\%$ , GND = 0 V, unless otherwise noted)

Item	Symbol	Min	Тур	Max	Unit	Tes	st Conditions
"H" input voltage	V <sub>IH</sub>	2.0		_	>		
"L" input voltage	V <sub>IL</sub>	_		0.8	V		
"H" output voltage	V <sub>OH</sub>	$V_{CC}-0.8$		_	V	$I_{OH} = -4 \text{ m}$	A
"L" output voltage	V <sub>OL</sub>	_	_	0.55	V	$I_{OL} = 4 \text{ mA}$	
"H" input current	Ін	_	_	1.0	μΑ	V <sub>I</sub> = V <sub>CC</sub>	$\overline{\text{WE}}$ , $\overline{\text{WRES}}$ , WCK, $\overline{\text{RE}}$ , $\overline{\text{RRES}}$ , RCK, $D_0$ to $D_7$
"L" input current	I <sub>IL</sub>	_		-1.0	μА	V <sub>I</sub> = GND	WE, WRES, WCK, RE, RRES, RCK, D <sub>0</sub> to D <sub>7</sub>
Off state "H" output current	I <sub>OZH</sub>	_	_	5.0	μΑ	$V_O = V_{CC}$	
Off state "L" output current	I <sub>OZL</sub>	_	_	-5.0	μΑ	V <sub>O</sub> = GND	
Operating mean current dissipation	Icc	_	_	120	mA	V <sub>I</sub> = V <sub>CC</sub> , GND, Output open	
						$t_{WCK}$ , $t_{RCK} = 25 \text{ ns}$	
Input capacitance	Cı	_		10	pF	f = 1 MHz	
Off state output capacitance	Co	_	_	15	pF	f = 1 MHz	·

#### **Function**

When write enable input  $\overline{WE}$  is "L", the contents of data inputs  $D_0$  to  $D_7$  are written into 1-line delay data only memory in synchronization with rise edge of write clock input WCK. At this time, the write address counter of 1-line delay data only memory is also incremented simultaneously.

The write functions given below are also performed in synchronization with rise edge of WCK.

When  $\overline{WE}$  is "H", a write operation to 1-line delay data only memory is inhibited and the write address counter of 1-line delay data only memory is stopped.

When write reset input WRES is "L", the write address counter of 1-line delay data only memory is initialized.

When read enable input  $\overline{RE}$  is "L", the contents of 1-line delay data only memory are output to data outputs  $Q_{00}$  to  $Q_{07}$  and those of 2-line delay data only memory to data outputs  $Q_{10}$  to  $Q_{17}$  in synchronization with the rise of read clock input RCK. At this time, the read address counters of 1-line and 2-line delay data only memories is also incremented simultaneously.

Moreover, data of  $Q_{00}$  to  $Q_{07}$  are written into 2-line delay data only memory in synchronization with rise edge of RCK. At this time, the write address of 2-line delay data only memory is incremented.

The read functions given below are also performed in synchronization with rise edge of RCK.

When  $\overline{RE}$  is "H", a read operation from both of 1-line delay data only memory and 2-line delay data only memory is inhibited and the read address counter of each memory is stopped. The outputs of  $Q_{00}$  to  $Q_{07}$  and  $Q_{10}$  to  $Q_{17}$  are in the high impedance state.

Moreover, a write operation to 2-line delay data only memory is inhibited and the write address counter of 2-line delay data only memory is stopped.

When read reset input  $\overline{RRES}$  is "L", the read address counter of 1-line delay data only memory, and the write address counter and read address counter of 2-line delay data only memory are initialized.

## **Switching Characteristics**

(Ta = 0 to 70°C,  $V_{CC}$  = 5 V  $\pm$  10%, GND = 0 V, unless otherwise noted)

Item	Symbol	Min	Тур	Max	Unit
Access time	t <sub>AC</sub>			18	ns
Output hold time	t <sub>OH</sub>	3			ns
Output enable time	t <sub>OEN</sub>	3	_	18	ns
Output disable time	t <sub>ODIS</sub>	3	_	18	ns

## **Timing Conditions**

(Ta = 0 to 70°C,  $V_{CC}$  = 5 V  $\pm$  10%, GND = 0 V, unless otherwise noted)

Item	Symbol	Min	Тур	Max	Unit
Write clock (WCK) cycle	t <sub>WCK</sub>	25			ns
Write clock (WCK) "H" pulse width	twckh	11			ns
Write clock (WCK) "L" pulse width	twckl	11			ns
Read clock (RCK) cycle	t <sub>RCK</sub>	25			ns
Read clock (RCK) "H" pulse width	t <sub>RCKH</sub>	11			ns
Read clock (RCK) "L" pulse width	t <sub>RCKL</sub>	11			ns
Input data setup time to WCK	t <sub>DS</sub>	7			ns
Input data hold time to WCK	t <sub>DH</sub>	3			ns
Reset setup time to WCK or RCK	t <sub>RESS</sub>	7			ns
Reset hold time to WCK or RCK	t <sub>RESH</sub>	3			ns
Reset nonselect setup time to WCK or RCK	t <sub>NRESS</sub>	7			ns
Reset nonselect hold time to WCK or RCK	t <sub>NRESH</sub>	3			ns
WE setup time to WCK	t <sub>WES</sub>	7	_	_	ns
WE hold time to WCK	t <sub>WEH</sub>	3		_	ns
WE nonselect setup time to WCK	t <sub>NWES</sub>	7			ns
WE nonselect hold time to WCK	t <sub>NWEH</sub>	3			ns
RE setup time to RCK	t <sub>RES</sub>	7		_	ns
RE hold time to RCK	t <sub>REH</sub>	3	_	_	ns
RE nonselect setup time to RCK	t <sub>NRES</sub>	7			ns
RE nonselect hold time to RCK	t <sub>NREH</sub>	3			ns
Input pulse rise/fall time	tr, tf	_		20	ns
Data hold time*	t <sub>H</sub>	_		20	ms

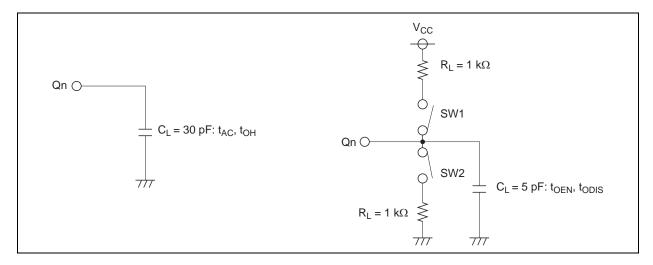
Notes: Reset the IC after power is turned on.

 $\overline{WE}$  "H" level period  $<20~ms-5120~t_{WCK}-\overline{WRES}$  "L" level period

 $\overline{RE}$  "H" level period  $<20~ms-5120~t_{RCK}-\overline{RRES}$  "L" level period

<sup>\*</sup> For 1-line access, the following should be satisfied:

### **Test Circuit**



Input pulse level: 0 to 3 V

Input pulse rise/fall time: 3 ns Decision voltage input: 1.3 V

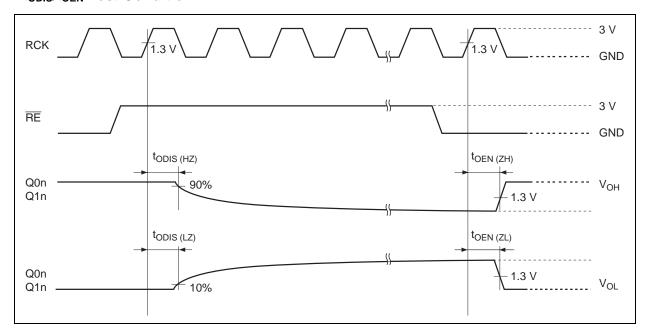
Decision voltage output: 1.3 V (However,  $t_{ODIS\,(LZ)}$  is 10% of output amplitude and  $t_{ODIS\,(HZ)}$  is 90% of that for

decision)

The load capacitance  $C_L$  includes the floating capacitance of connection and the input capacitance of probe.

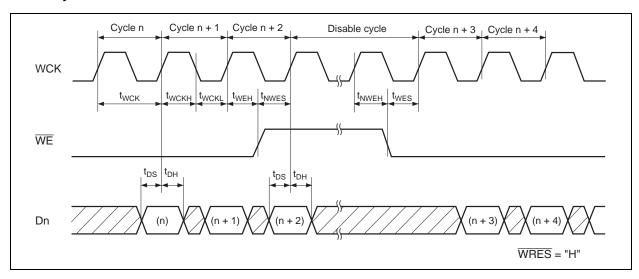
Parameter	SW1	SW2
todis (LZ)	Closed	Open
todis (HZ)	Open	Closed
toen (ZL)	Closed	Open
t <sub>OEN (ZH)</sub>	Open	Closed

### todis/toen Test Condition

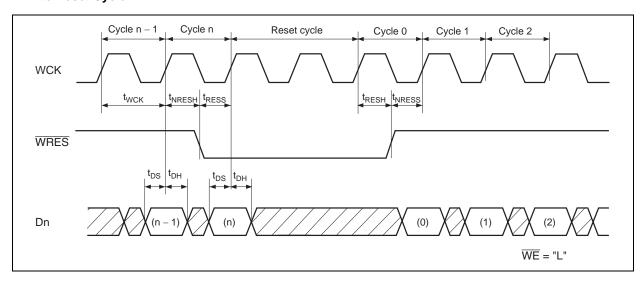


## **Operating Timing**

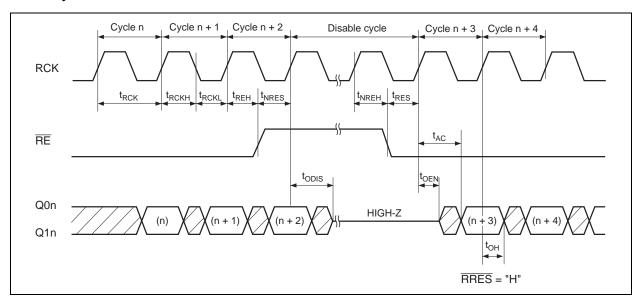
### Write Cycle



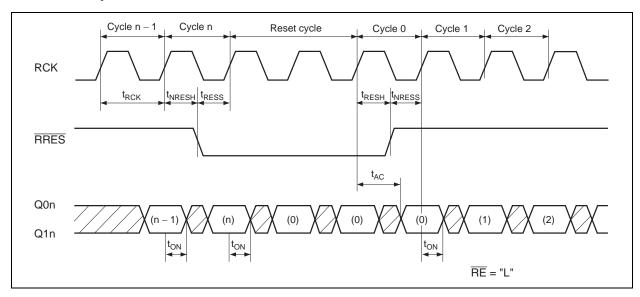
### **Write Reset Cycle**



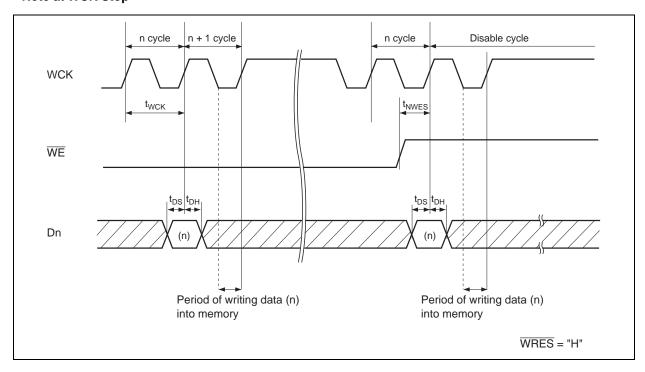
### **Read Cycle**



### **Read Reset Cycle**



### **Note at WCK Stop**



Input data Dn of n cycle is read at the rising edge after WCK of n cycle. Writing operation starts in the "L" period of WCK of n + 1 cycle and ends at the rising edge after n + 1 cycle.

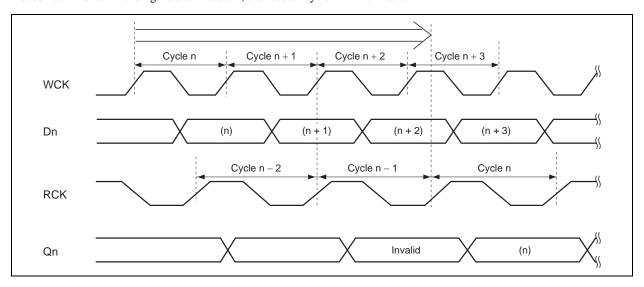
To stop reading write data at n cycle, input WCK for up to the rising edge of n+1 cycle.

When the cycle next to n cycle is a disable cycle, input of WCK for a cycle is required after a disable cycle as well.

### Shortest Read of Data "n" Written in Cycle n

(Cycle n-1 on read side should be started after end of cycle n+1 on write side)

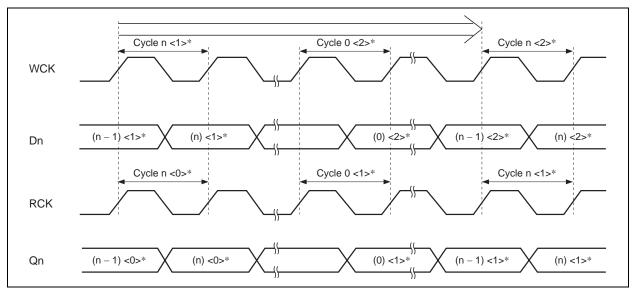
When the start of cycle n-1 on read side is earlier than the end of cycle n+1 on write side, output Qn of cycle n becomes invalid. In the figure shown below, the read of cycle n-1 is invalid.



#### Longest Read of Data "n" Written in Cycle n: 1-line Delay

(Cycle n <1>\* on read side should be started when cycle n <2>\* on write is started)

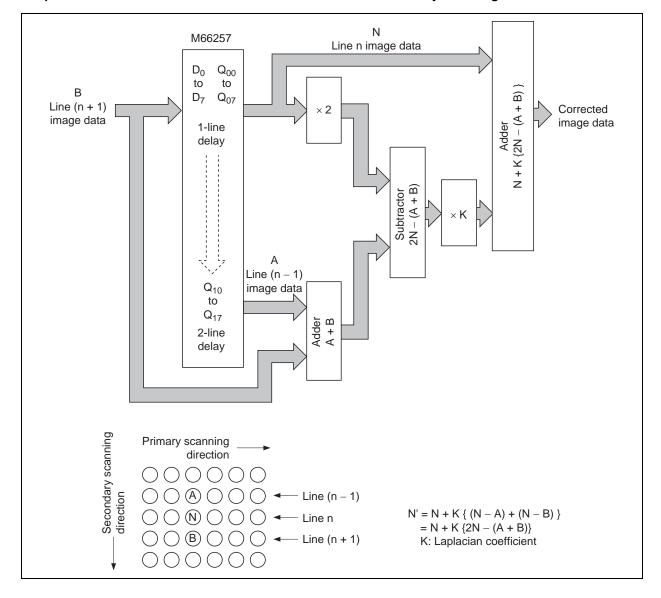
Output Qn of n cycle <1>\* can be read until the start of reading side n cycle <1> and the start of writing side n cycle <2>\* overlap each other.



Note: <0>\*, <1>\* and <2>\* indicates a line value.

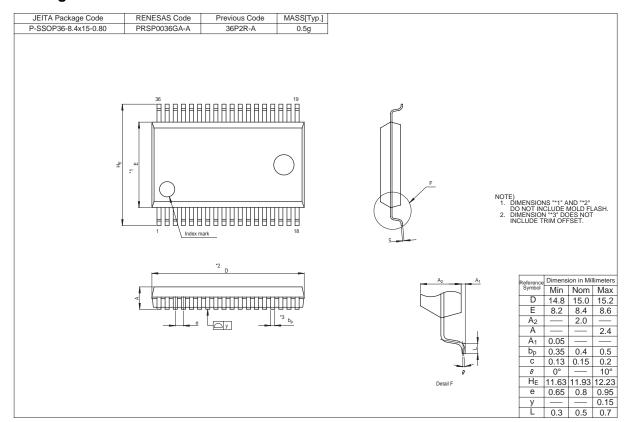
## **Application Example**

### Laplacian Filter Circuit for Correction of Resolution in the Secondary Scanning Direction



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### **Package Dimensions**



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